
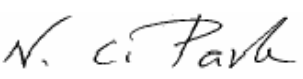
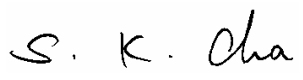


EMC Test Report

According to FCC Part 15 Subpart B

Project No.	LBE051171
Equipment under Test	
Applicant	Samsung Electronics Co., Ltd
Address	416 Maetan3-Dong, Yeongtong-Gu, Suwon-Si, Gyeonggi-Do, Korea, 443-742
Product Name	LCD Monitor
Model Name	SO37UO
Manufacturer	SAMSUNG
Brand Name	SAMSUNG
Variant Model	See Page 3
FCC ID	A3LSO37UO
Date of Test	May 20 , 2005 ~ May 30, 2005
Issued Date	May 31, 2005

	Name/Position	Signature
Tested by	Tae Young, Jang Test Engineer	
Reviewed by	No Cheon, Park Manager of EMC Lab.	
Authorized by	Seung Kyu, Cha Chief of EMC Lab.	

1. This test reports does not constitute an endorsement by NIST/NVLAP or U.S Government.
2. This test report is to certify that the tested device properly complies with the requirements of FCC Rules and Regulations Part 15 Subpart B Unintentional Radiators.
All tests necessary to show compliance to the requirements were and these results met the specifications requirement.

This laboratory is registered by the NIST/NVLAP, U.S.A.

The test reported herein have been performed in accordance with its terms of registration.



NVLAP LAB CODE 200623-0

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1. General Information

1.1 Basic Information related Product

Applicant	Samsung Electronics Co., Ltd
Model name	SO37UO
Applicant Address	416 Maetan3- Dong, Yeongtong-Gu, Suwon-Si, Gyeonggi-Do, Korea, 443-742
Contact Person	Chang Young, Choi
Kind of product	LCD Monitor
Valiant list	
Manufacturer	Samsung Electronics Co., Ltd

1.2 Detail Information related Product

Specification

Image Viewable Image Size	37 Inch
Maximum Resolution	1360 X 768@60Hz
Horizontal Frequency	30 ~ 60KHz
Vertical Frequency	60 ~ 75Hz

1.3 Operating Mode and Condition

The system was configured for testing in typical fashion use. Cables were attached to each of the available I/O Ports. Where applicable, peripherals were attached to the I/O cables. The mode of operation utilized for testing was selected to best simulate typical EUT use.

- PC Analog In

1.4 Equipment Modifications

No equipment modifications were required.

1.5 Test Configuration

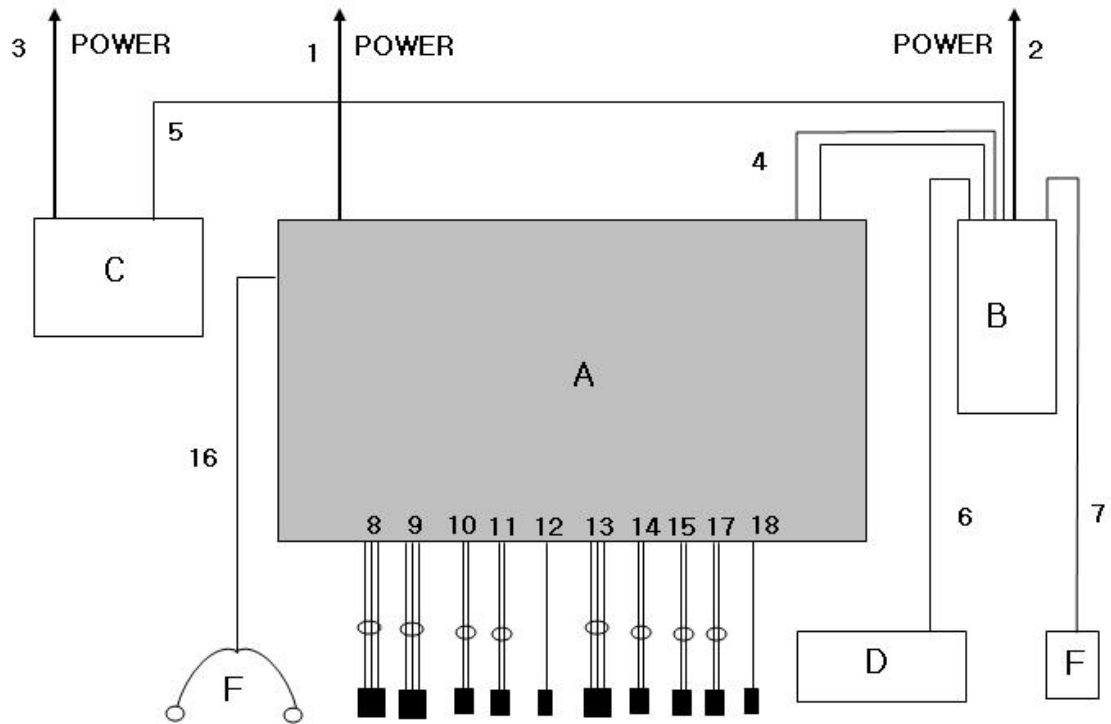
Used EUT and Peripherals

Seq	Device	Model Name	Serial #	Maker	FCC ID
A	LCD Monitor	SO37UO	-	SAMSUNG	A3LSO37UO
B	Personal Computer	M6050	812092FRCO1963	SAMSUNG	DoC
C	Printer	ML-1740	BABX820386E	SAMSUNG	A3LML-1710P
D	PS/2 Keyboard	SEM-DC8H	85011702	SAMSUNG	E2XSEM-DC8H
E	PS/2 Mouse	P801	02053838	SAMSUNG	FSUGMZFT
F	Head Set	-	-	-	-

Port Description

	Connect Cable	Length [m]	Shielded [Y/N]	Remark
1	Power	1.8	No	To the Mains
2	Power	1.8	No	To the Mains
3	Power	1.8	No	To the Mains
4	Monitor (PC Video Input)	1.7	Yes	To the PC
5	Parallel (Printer)	1.8	Yes	To the PC
6	PS/2 (Keyboard)	1.5	No	To the PC
7	PS/2 (Mouse)	1.5	No	To the PC
8	Component In 1	1.5	No	Termination
9	Component In 2	1.5	No	Termination
10	Audio In 1	1.5	No	Termination
11	Audio In 2	1.5	No	Termination
12	S-video In	1.5	No	Termination
13	AV In	1.5	No	Termination
14	Audio Out	1.5	No	Termination
15	PC audio in	1.5	No	To the PC
16	Head Set	1.5	No	To the EUT
17	DVI Audio In	1.5	No	Termination
18	HDMI In	1.5	No	Termination

Block Diagram



1.6 Applied Standards

List

Applied Standards	Test Procedure
FCC Part15 Subpart B	ANSI C63.4 : 2003

1.7 Test Facility

General Information

The sites are constructed in conformance with the requirements of ANSI C63.4 and CISPR 16-1, 16-2.

This EMC Testing Lab. is accredited by Korea Laboratory Accreditation Scheme(KOLAS) which signed the International Laboratory Accreditation Cooperation (ILAC) Mutual Recognition Arrangement (MRA) for the above test item(s) and test method(s).

This Lab. is operated as testing laboratory in accordance with the requirements of ISO/IEC 17025:1998.

Accreditation and Listing



Uncertainty

(According to NAMAS Pub.NIS81)

Test Item	Expanded Uncertainty
Radiated Emission	±5.09
Conducted Emission	±3.30

2. Summary of Test Results

Result : PASS

The equipment under test(EUT) has been found to comply with the applied standards.

Test Name	Applied Standard	Result	
Electromagnetic Emission Test			
3.1	Conducted Emission	FCC Part15 Subpart B	Complied
3.2	Radiated Emission	FCC Part15 Subpart B	Complied

3. Description of Individual Tests

3.1 Conducted Emission

Test Information	
Test Engineer	Tae Young, Jang
Test Date	May 30, 2005
Climate Condition	Ambient Temperature : 23 °C Relative Humidity : 35%
Test Place	Shield Room #5

Test Equipments

Equipment	Modal Name	Manufacturer	Serial No.	Calibration	
				Next Date	Interval
Test Software	EP5CE	TOYO	None	N/A	N/A
Field strength meter	ESI-26	R&S	832692/002	2006-02-26	12
TV Signal Generator	PM5418-TDSI	PHILIPS	LO612437	2005-09-23	12
Field strength meter	ESS	R&S	844661/005	2006-01-11	12
L.I.S.N	ESH3-Z5	R&S	100261	2005-07-23	12
L.I.S.N	ESH3-Z5	R&S	847265/028	2005-09-12	12

EUT Test Setup

The EUT was set up as per normal use on a wooden table, 0.4m from a vertical ground reference plane, at least 0.8m from other conduction surfaces and 0.8m from the LISN.

See photo.

Test Result

Measurement Results	<p>Pass</p> <p>The measured emissions of the EUT have found to be below the specified limits.</p>
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3.2 Radiated Emission

Test Information	
Test Engineer	Tae Young, Jang
Test Date	May 20 , 2005
Climate Condition	Ambient Temperature : 24 °C Relative Humidity : 33%
Test Place	10m Semi-anechoic Chamber

Test Equipments

Equipment	Modal Name	Manufacturer	Serial No.	Calibration	
				Next Date	Interval
RF Selector	NS4900	TOYO	0303-015	N/A	N/A
Bi-log Antenna	6112B	SCHAFFNER	2766	2005-07-06	12
Mast Controller	HD2000	HD	HD20000902027	N/A	N/A
Test Software	EP5RET	TOYO	None	N/A	N/A
Test Software	EP5RE	TOYO	None	N/A	N/A
TV Signal Generator	PM5418-TDSI	PHILIPS	LO612437	2005-09-23	12
EMC Analyzer	E7405A	Agilent	MY42000052	2005-08-26	12
Field strength meter	ESCS30	R&S	839809/002	2006-05-04	12
RF Amplifier	8447D	Agilent	2944A10430	2005-07-20	12
Mast Controller	HD 100	HD	100/374	N/A	N/A

EUT Test Setup

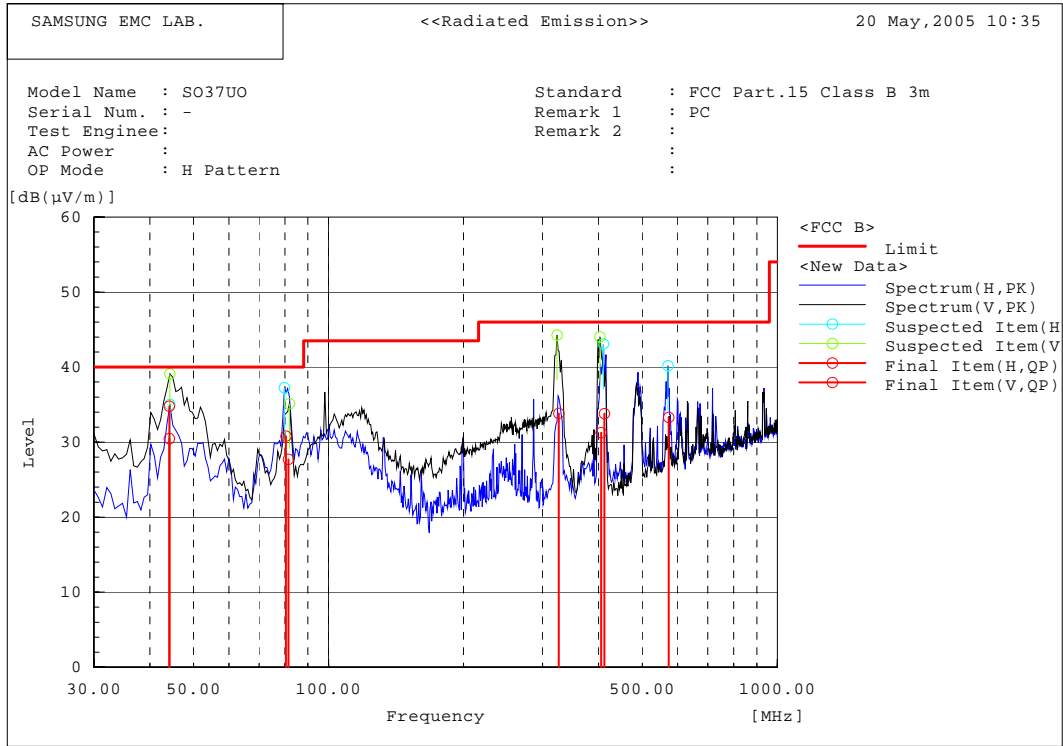
EUT is positioned at 3m from antenna at the center of the table in the semi-anechoic chamber.
All unused ports were terminated into characteristic loads.

Test Result

Measurement Results	<p>Pass</p> <p>The measured emissions of the EUT have found to be below the specified limits.</p>
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Test Data (Local Oscillator)

■ Operating Mode : PC Analog in(30MHz ~ 1GHz)



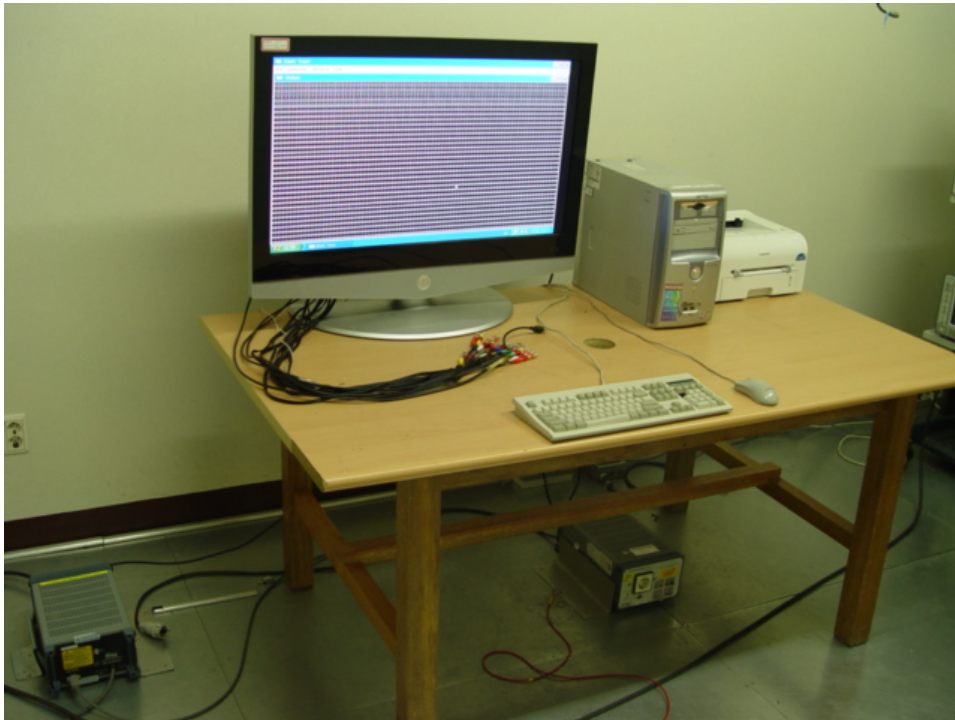
Final Result

--- Horizontal Polarization (QP)---							
No.	Frequency [MHz]	Reading [dB(µV)]	c.f [dB(1/m)]	Result [dB(µV/m)]	Limit [dB(µV/m)]	Margin [dB]	Remark
1	44.202	46.0	-15.5	30.5	40.0	9.5	
2	80.362	49.0	-18.2	30.8	40.0	9.2	
3	411.720	39.0	-5.2	33.8	46.0	12.2	
4	572.808	35.0	-1.7	33.3	46.0	12.7	

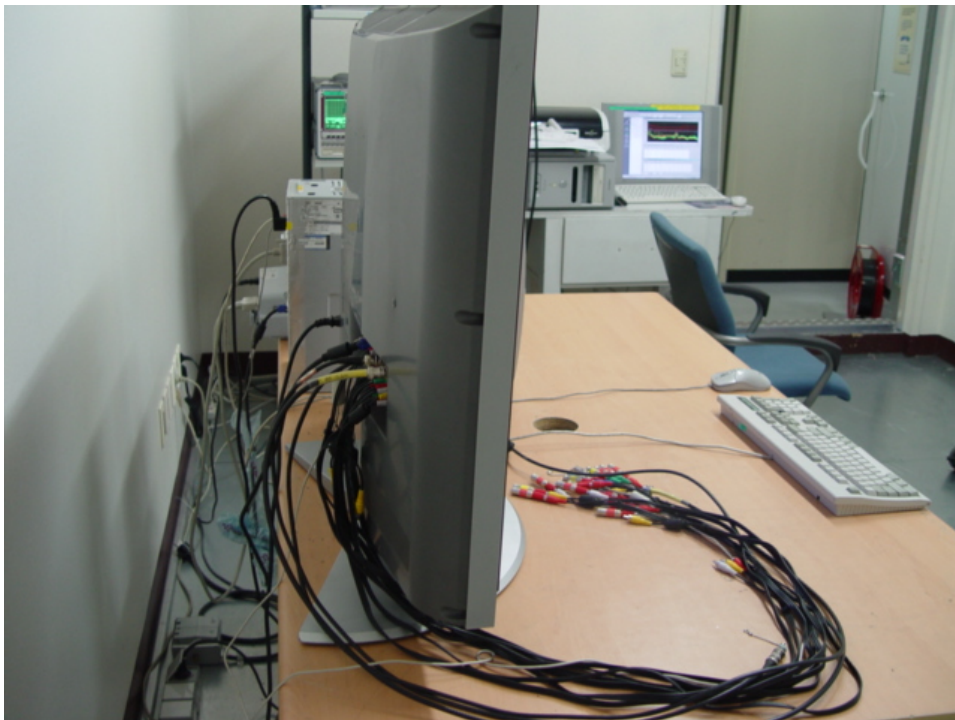
--- Vertical Polarization (QP)---							
No.	Frequency [MHz]	Reading [dB(µV)]	c.f [dB(1/m)]	Result [dB(µV/m)]	Limit [dB(µV/m)]	Margin [dB]	Remark
1	44.202	50.3	-15.5	34.8	40.0	5.2	
2	81.368	45.8	-18.1	27.7	40.0	12.3	
3	325.708	41.4	-7.6	33.8	46.0	12.2	
4	405.000	36.7	-5.4	31.3	46.0	14.7	

4. Appendix A

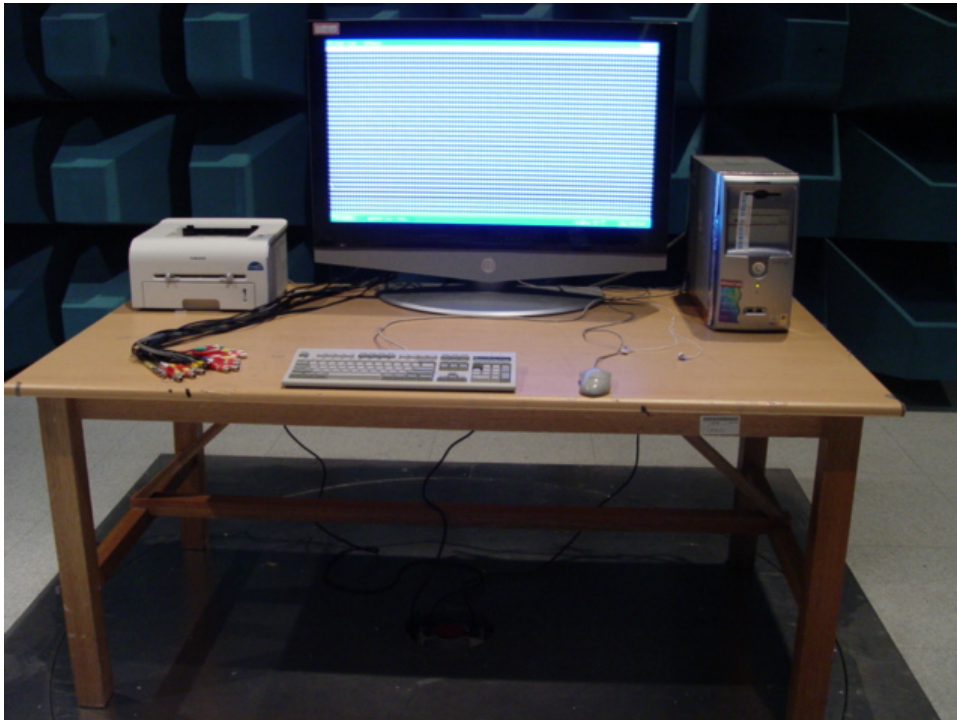
4.1 Test Photography



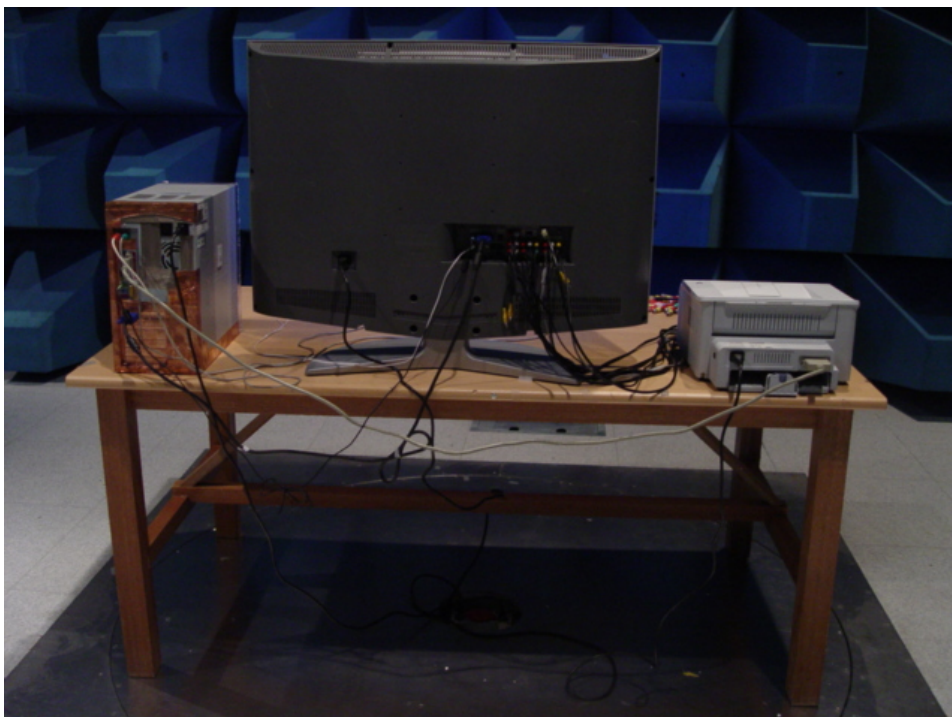
Picture 1. Conducted Emission (Front view)



Picture 2. Conducted Emission (Rear view)



Picture 3. Radiated Emission (Front view)



Picture 4. Radiated Emission (Rear view)

4.2 EUT Photography



Picture 5. EUT (Front view)



Picture 6. EUT (Rear view)